

Class	Subclass	ISSUE CLASSIFICATION

PATENT NUMBER

U.S. UTILITY Patent Application

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APPLICATION NO. 09/866651	CONT/PRIOR F	CLASS 25 324	SUBCLASS 24 750	ART UNIT 201 2829	EXAMINER SANTIAGO NGUYEN, ANH P.
APPLICANTS Masaaki Hiroki					
TITLE Device for inspecting element substrates and method of inspection using this device					
PTO-2040 12/98					

The term of this patent shall not extend beyond the expiration date of this Patent No. _____

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